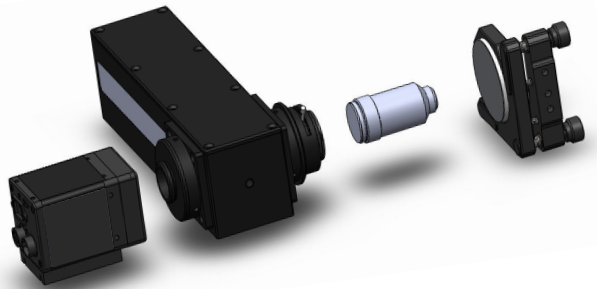


# Kaleo Kit

Fully modular  
metrology solution  
from UV to IR

**PHASICS**  
the phase control company



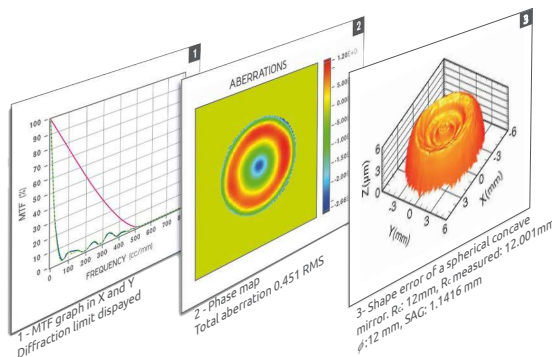


# ASSEMBLE YOUR OWN MODULAR METROLOGY SYSTEM...

With the rise in complexity of optical systems, metrology teams often need **specific measurement parameters** (test wavelength, accuracy, resolution, relevant outcomes...). PHASICS answers this challenge with **Kaleo Kit**, its modular system for optics qualification.

**Kaleo Kit** is the combination of a broad range of compatible modules, that let you create a **cost-effective, compact, and easy-to-use system** that can adapt to a wide range of measurement configurations and ensure the quality of your sample at all development stages.

Access all the characteristics of your sample in a **single shot acquisition**: TWE, RWE, wavefront aberrations, MTF, PSF, and a lot more!



# ... IN JUST 3 EASY STEPS

# 1

Choose **YOUR**  
Wavefront Sensor



<b>SID4 Model</b>	<b>Spectral Range (nm)</b>	<b>Sampling (px)</b>
<b>SID4-UV</b>	250-400	250x250
<b>SID4</b>	400-1100	160x120
<b>SID4-HR</b>	400-1100	400x300
<b>SID4-SWIR</b>	900-1700	80x64
<b>SID4-SWIR-HR</b>	900-1700	160x128
<b>SID4-DWIR</b>	3000-5000	160x120

# 2

Select **YOUR**  
R-Cube

**Wavelength \*  
(nm)**

365	810
405	850
530	940
625	1050
740	1550
780	3900

# 3

Shape **YOUR** beam

**Beam Expander \***  
Exit pupil  
diameter (mm)

8  
15  
30  
60  
130

OR

**Focusing  
System \***  
F#

0.6  
1  
1.6  
2.5  
5  
10

+ Reference mirror (flat or sphere)

\* more options upon request

# ACCORDING TO YOUR SPECIFIC REQUIREMENTS

## VERSATILE

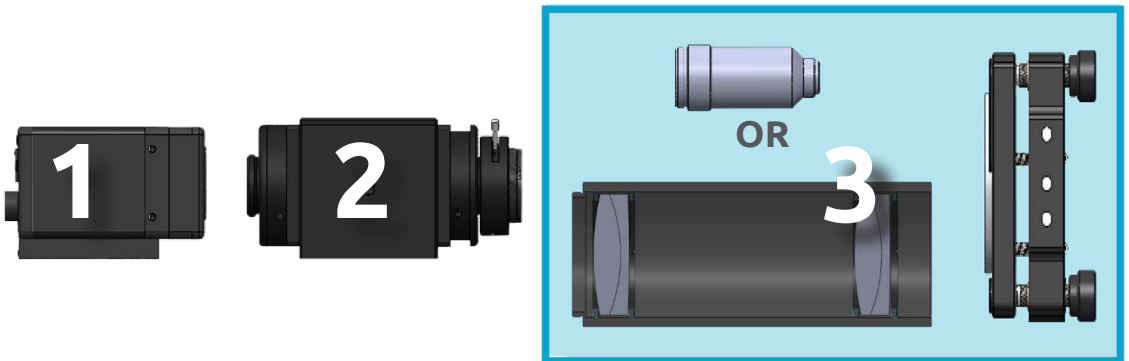
- Available from UV to IR
- Modules compatible with stand-alone use
- All measurement configurations: finite-finite, infinite-finite...
- Same modules fit for different setups

## POWERFUL UNIQUE TECHNOLOGY

- High resolution
- Dedicated to large aberrations measurement
- Achromatic measurement: for any test wavelength
- Nanometric sensitivity

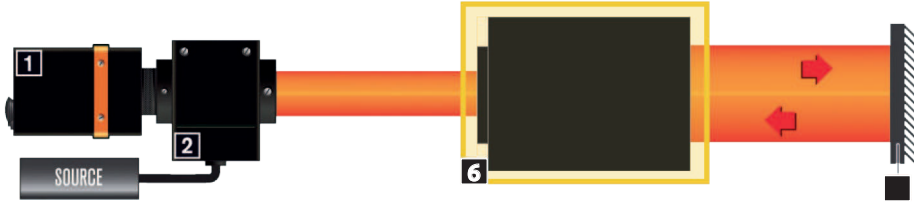
## EASY-TO-USE

- Compact
- Designed for easy alignment
- Quick access to all results



# ADAPTED TO ALL APPLICATIONS

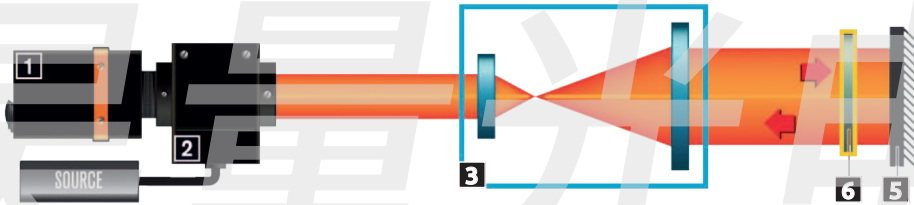
- Telescope alignment and characterization



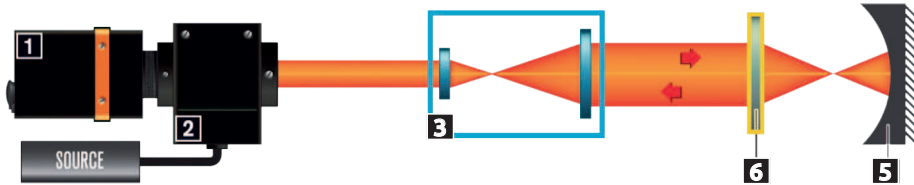
- Concave mirror measurement



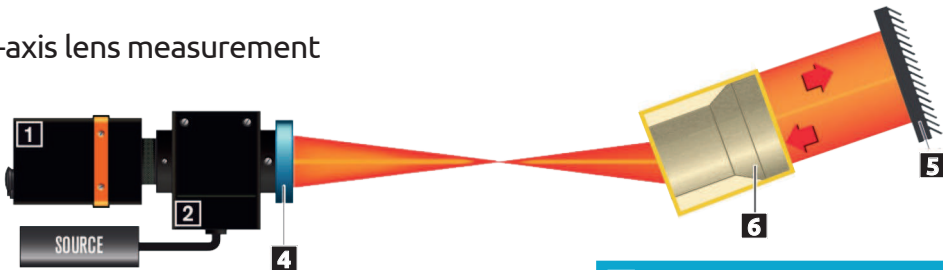
- Large diameter flat optics characterization: Filters, Windows, Polarizing optics



- Large diameter lens & objective measurement in any configuration



- Off-axis lens measurement



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1	SID4 Wavefront sensor
2	R-Cube
3	Beam expander
4	Focusing system
5	Reference mirror
6	System under test

Kaleo Kit modules